

2010

# EECE 310 Lab Report for Experiment 10

## MOS TRANSISTOR

Prepared and done by Noor S Afif  
201001275  
nsa45@aub.edu.lb  
Section 3    Bench 5



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## **I. Objectives**

The purpose of the following experiment is to investigate the characteristics of a Metal-Oxide-Semiconductor Field-Effect Transistor, also known as a MOSFET.

Another purpose of this lab is to study a MOSFET's applications as a:

- Voltage-Controlled Resistor.
- Logic Gate.
- Amplifier.
- Current Source.

## **II. Lab Equipment Used**

- DDM: Digital Device Multimeter.
- Breadboard.
- Function Generator.
- Oscilloscope.
- The Tektronix PS 280-Power Supply

## **III. Lab Tools and Components Used**

- Wire Stripper
- Wire Cutter

## **IV. Components Used**

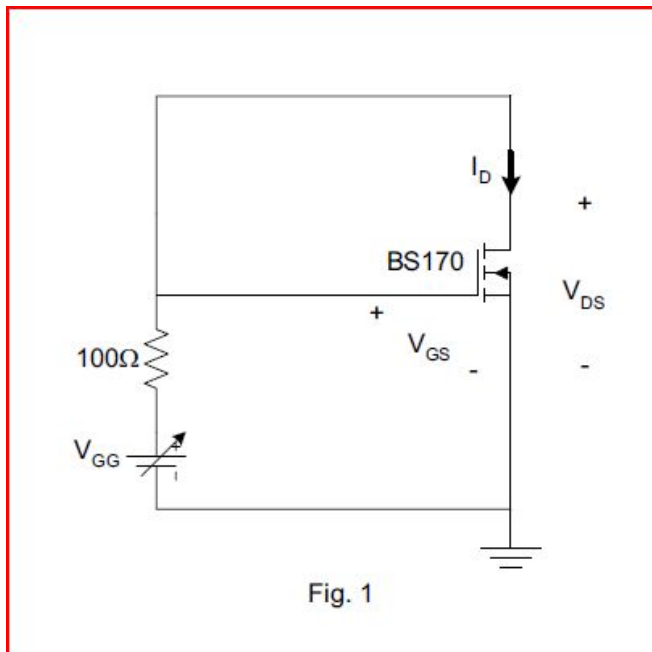
Theoretical Value	Measured Value	% error
100 $\Omega$	100.39 $\Omega$	0.39
220 $\Omega$	219 $\Omega$	0.45
330 $\Omega$	335 $\Omega$	1.51
470 $\Omega$	476 $\Omega$	1.27
560 $\Omega$	550 $\Omega$	1.78
680 $\Omega$	660 $\Omega$	2.94
820 $\Omega$	808 $\Omega$	2.68
1 k $\Omega$	1.007k $\Omega$	0.7
3.3 k $\Omega$	3.2k $\Omega$	3.03
4.7 k $\Omega$	4.678k $\Omega$	0.468
10 k $\Omega$	9.86k $\Omega$	1.4
15 k $\Omega$	14.98k $\Omega$	0.134

- Connection Wires.
- Capacitors of value 10  $\mu$ F.
- BS170 MOSFET

## V. Experimental Procedure and Discussion

### A. MOSFET Characteristics

#### A1. Circuit Diagrams



#### A2. Detailed Experimental Procedure

i-Connect the circuit of Fig 1 on the breadboard, use a DDM to measure  $I_D$ .

ii-The connections allow us to determine the characteristics of the MOSFET, specifically the transconductance parameter  $k$ , and the threshold voltage  $V_T$ .

Those 2 characteristics allow us to calculate the drain current in saturation.

Where  $I_D = (k/2)(V_{GS} - V_T)^2$  when  $V_{GS} > V_T$  and  $V_{DS} > V_{GS} - V_T$

In the given case  $V_{DS} = V_{GS}$  and since  $V_T$  is positive in the current MOSFET, the transistor is in saturation whenever  $V_{GS} > V_T$ .

In order to calculate two variables we need two measurements. We measure  $V_{GS}$  when  $I_D = 10\text{mA}$  and another time when  $I_D = 25\text{mA}$ .

#### A3. Measurements and Results

i- Starting with  $V_{GG} = 0.5\text{V}$  (on the Tektronix PS 280) slowly increase its value until  $I_D = 10\text{mA}$  ( visible on the DDM) that occurs when  $V_{GS} = 2.16\text{V}$   
Continue increasing until  $I_D = 25\text{mA}$  which happens when  $V_{GS} = 2.43\text{V}$

Solve for  $K$  and  $V_T$  using the 2 equations:

$$10 = (k/2)(2.16 - V_T)^2$$

$$25 = (k/2)(2.43 - V_T)^2$$

Which yields to  $k = 925.25 \text{ mA/V}^2$  and  $V_T = 2\text{V}$

ii - Calculation of error percentage.

Increase  $V_{GG}$  till  $I_D = 40 \text{ mA}$ , which yields a measured value of  $V_{GS} = 2.6\text{V}$

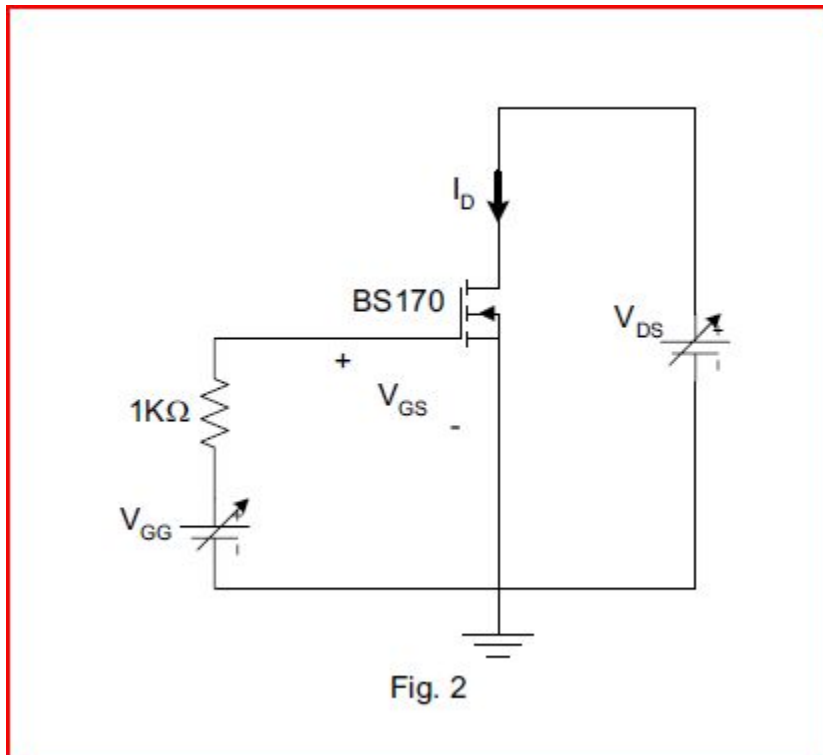
Meanwhile, according to the formula  $V_{GS} = V_T + \sqrt{2 I_D / k}$

Calculated  $V_{GS} = 2.29 \text{ V}$ .

Error Percentage =  $(2.29 - 2.6) * 100 / 2.29 = 13 \%$

## B. MOSFET as a Voltage-Controlled Resistor

### B1. Circuit Diagrams



### B2. Detailed experimental procedure

Using connections of Fig.2 and the value of  $V_T = 2\text{V}$  (calculated above) set  $V_{GG} = V_T + 2\text{V}$

i- Using the power supply, apply  $V_{DS}$ , and measure  $I_D$  using a DDM.

ii- Since the gate current of the MOSFET = 0,  $V_{GS} - V_T = 2\text{V}$

### B3. Measurements and Results

i-Table  $V_{GS}-V_T=2V$

$V_{GS}-V_T=2V$	
$V_{DS}(V)$	$I_D(mA)$
0.1	6.67
0.2	13.4
0.3	21.2

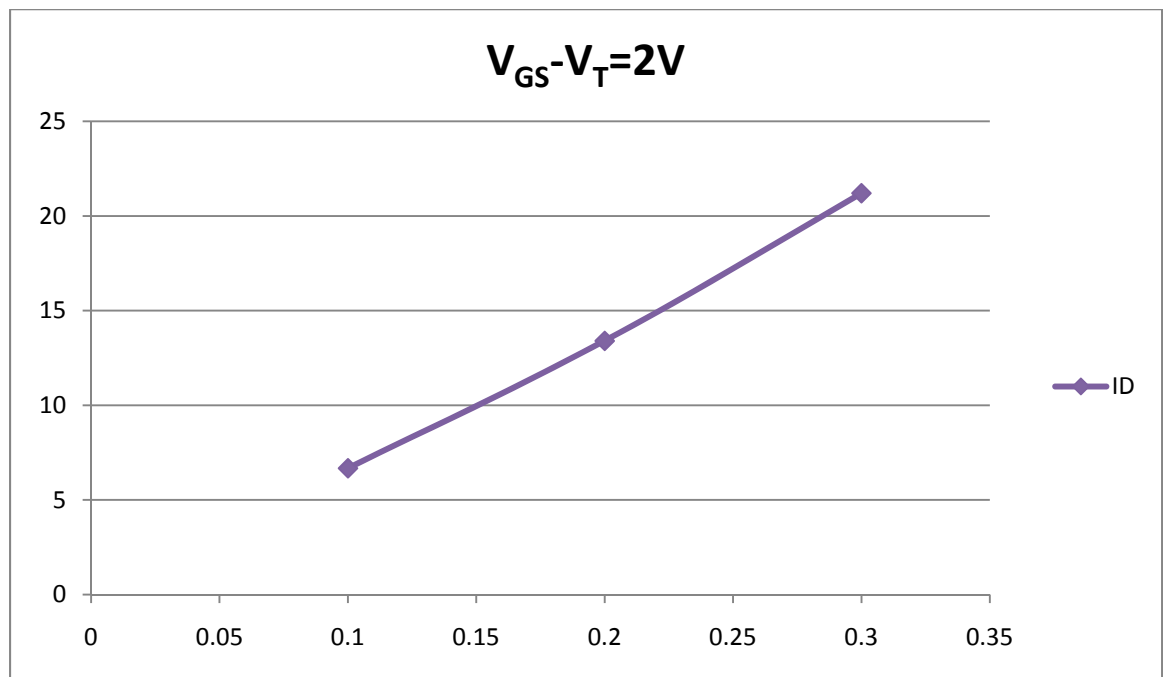
ii-Table  $V_{GS}-V_T=3V$

$V_{GS}-V_T=3V$	
$V_{DS}(V)$	$I_D(mA)$
0.1	10.8
0.2	14.65
0.3	23.65

### B4. Discussion

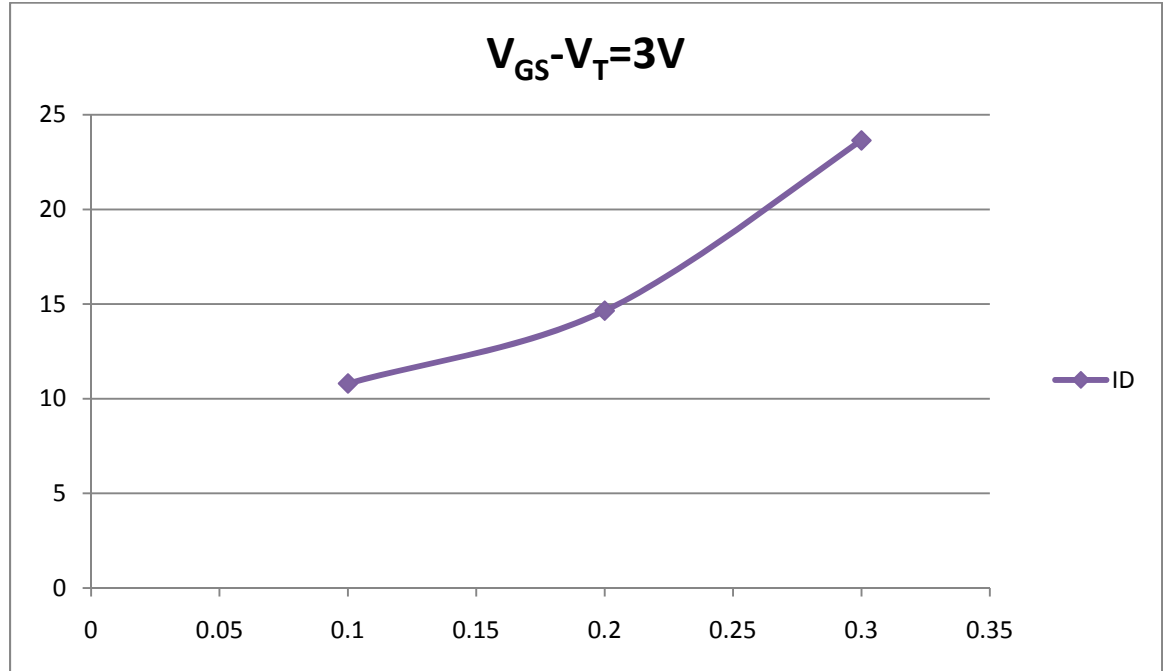
i-Curve for  $I_D$  versus  $V_{DS}$

a-  $V_{GS}-V_T=2V$





b-  $V_{GS}-V_T=3V$



ii-Find the slope

a-  $V_{GS}-V_T=2V$

$$\text{Slope}=(21.2-6.67)/0.2=72.45 \text{ mA/V}$$

b-  $V_{GS}-V_T=3V$

$$\text{Slope}=(23.65-10.8)/0.2=64.25 \text{ mA/V}$$

iii-Find the resistance (Table)

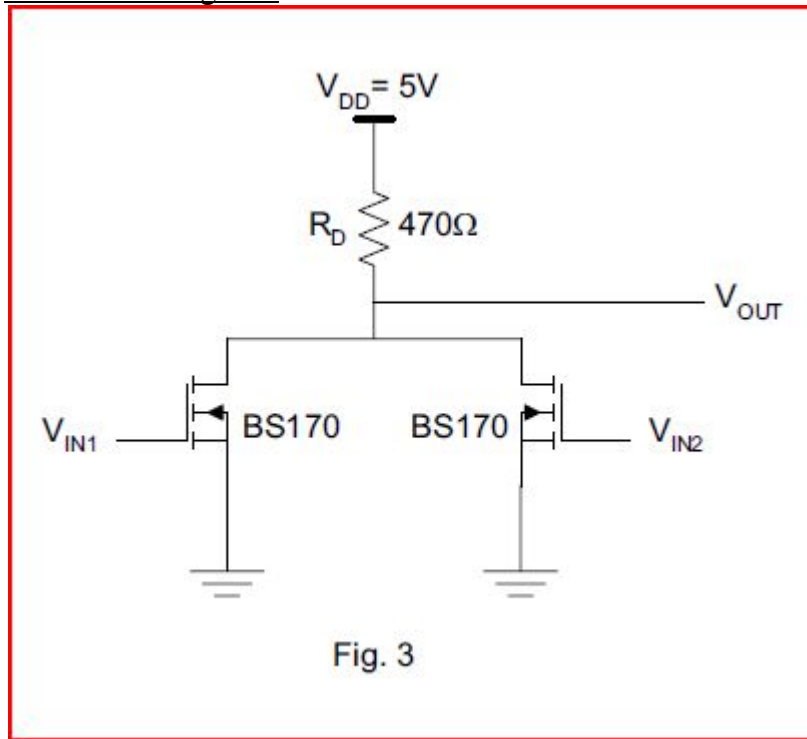
$V_{GS}-V_T(V)$	$R_{DS}(\Omega)$
2	13.80
3	15.56

$R_{DS}$  is not constant but depends on  $V_{OV}$  therefore the MOSFET in this case is a voltage controller resistance, where  $R_D= V_{DS}/ I_D=1/(k V_{OV})$

And since  $V$  and  $I$  are related by a straight line , it is called linear, or ohmic( Resistance).

## C. MOSFET Logic Gate

### C1. Circuit Diagrams



### C2. Detailed Experimental Procedure

- i- Connect the circuit of Fig 3, measure  $V_{IN1}$ ,  $V_{IN2}$  &  $V_{OUT}$  using a DDM
- ii- This circuit implements a logic gate; we will determine in this part of the experiment the logic function of this gate and study its characteristics. There are two inputs IN1 and IN2, and one output OUT.

To build the truth table of this gate, we apply all possible combinations of inputs, and observe the output. Start with IN1 = logic 0 and IN2 = logic 0. To get a logic 0, we will connect the input nodes to ground. The value of the output in this case corresponds to logic 1.

### C3. Measurements and Results

Apply logic 1 at IN1, and logic 0 at IN2, and observe the output. Repeat for IN1 = logic 0, IN2= logic 1, and for IN1 = logic 1 and IN2 = logic 1.

i-Table C-1

IN1 (Logic)	IN2(Logic)	Out(Logic)	$V_{IN1}(V)$	$V_{IN2}(V)$	$V_{OUT}(V)$
0	0	1	0.0	0.0	5.03
0	1	0	0.0	5	0.01
1	0	0	5.02	0.0	0.012
1	1	0	5.012	5.03	0.009

From the truth table indicates that the logic function of this gate is a NOR gate.

ii-Table C-2

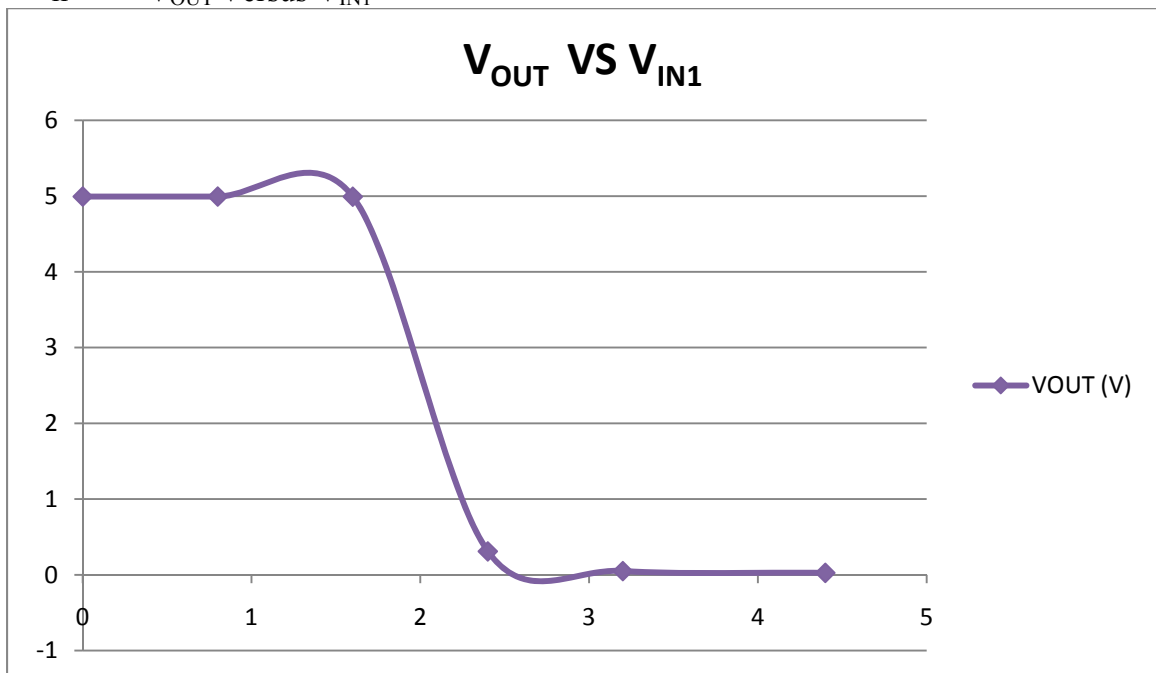
$V_{IN1}(V)$	$V_{OUT}(V)$	MOSFET Region	Out(Logic)
0	4.995	Cut Off	1
0.8	4.995	Cut Off	1
1.6	4.993	Cut Off	1
2.4	0.31	Triode	0
3.2	0.05	Triode	0
4.4	0.026	Triode	0

#### C4. Discussions

- i- The values of high that correspond to logic one are around 5, meanwhile the values of low that correspond to logic zero are around 0 or values in mV

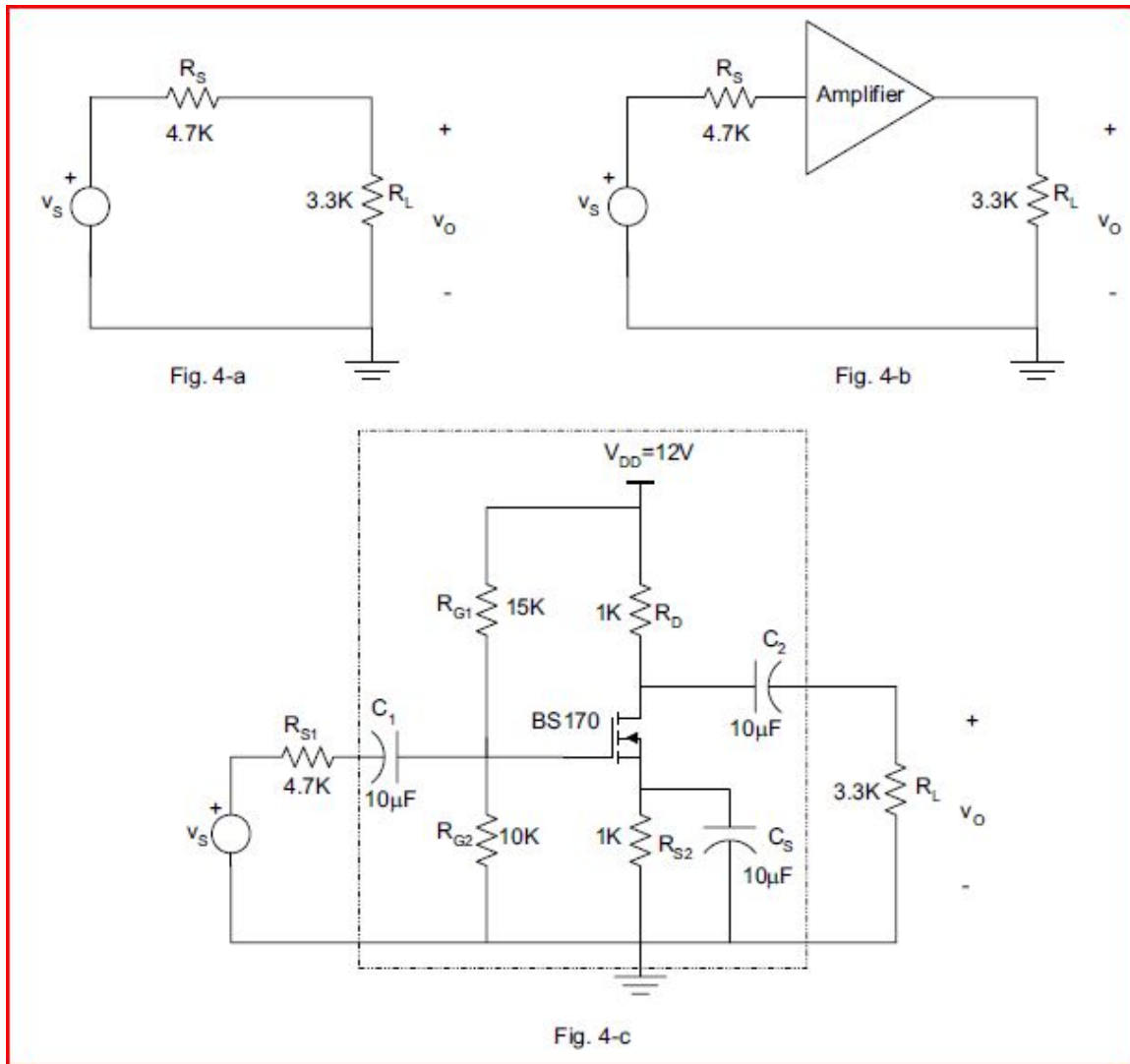
When the MOSFET is in the ohmic(linear) region the output is low, since the MOSFETs acts as voltage controlled resistors. It is clear in the figure that a change in  $R_D$  would induce a change in the opposite sense in the MOSFET resistance behavior, and also in  $V_{DS} = V_{OUT}$ . In conclusion increasing the resistance would induce a Low (0 logic) output.

- ii-  $V_{OUT}$  Versus  $V_{IN1}$



At  $V_{IN1} = 2.4 V$  the output switches. That occurs when  $V_{IN1} = V_{GS} > V_T$

D. MOSFET as an Amplifier  
D1.Circuit Diagrams



D2. Detailed experimental procedure

- i- Connect the figure 4-a with the voltage source equal to a 100mV pk-pk 10KHz sin signal.
- ii- Use an oscilloscope to measure  $V_o$ , voltage and current gain.

D3. Measurements And Results

i-	Value
$V_s$ pk-pk	103mV
$V_i$ pk-pk	74mV
$V_o$ pk-pk	16mV
Gain (V/V)	0.216

The current gain is 1, since it is the same node.

ii- Measurement Calculation.

DC Values	Measured	Calculated	Error %
$I_D$	2.59 mA	0	1
$V_{GS}$	4.823V	5	3.669
$V_{DS}$	6.93 V	7	1.01

D4.Discussion

The presence of a capacitance limits the MOSFET.

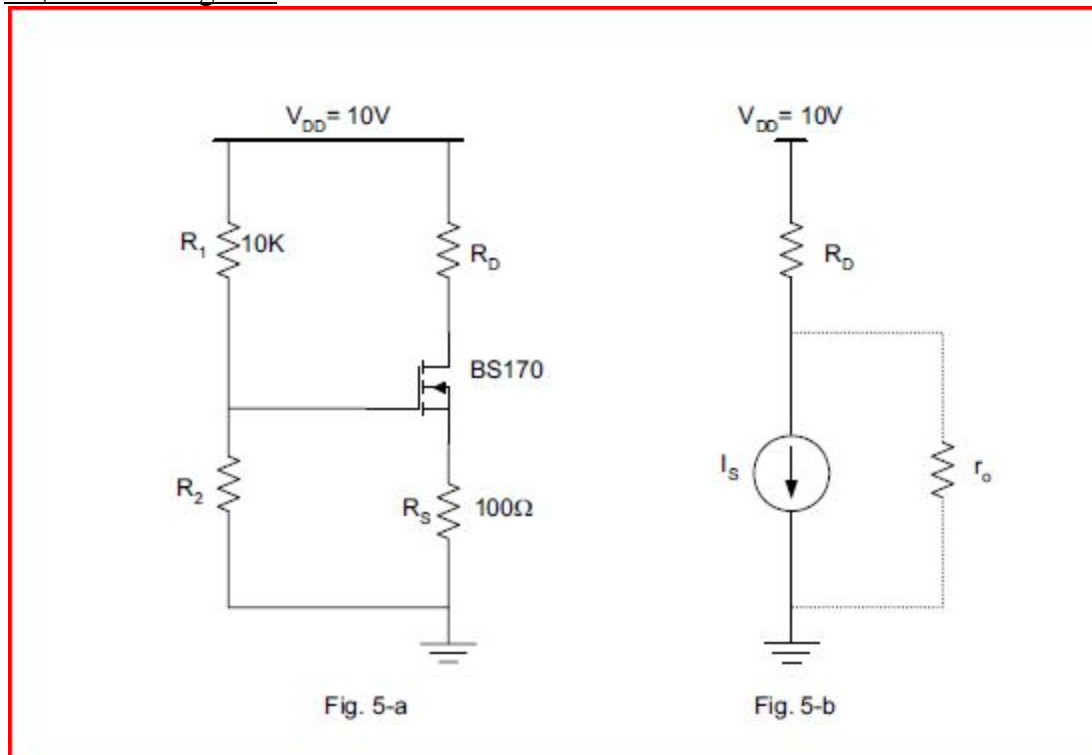
Where at low frequencies, the gain decreases due to the increase of the capacitors performance, which is similar to an open circuit behavior. C2 affects the voltage output in reducing it, and thus reducing the gain.

Meanwhile at high frequencies, the gain increases, since the capacitance acts a short circuit.

The voltage gain of a BJT is lower, than that of an amplifier.

E. MOSFET as a Current Source.

E1, Circuit Diagrams



E2.Detailed Experimental Procedure

i-Connect fig 5-a , which is similar but not a BTJ, this circuit doesn't use a Zener Diode.

ii-Use the values of K and  $V_T$  found previously.

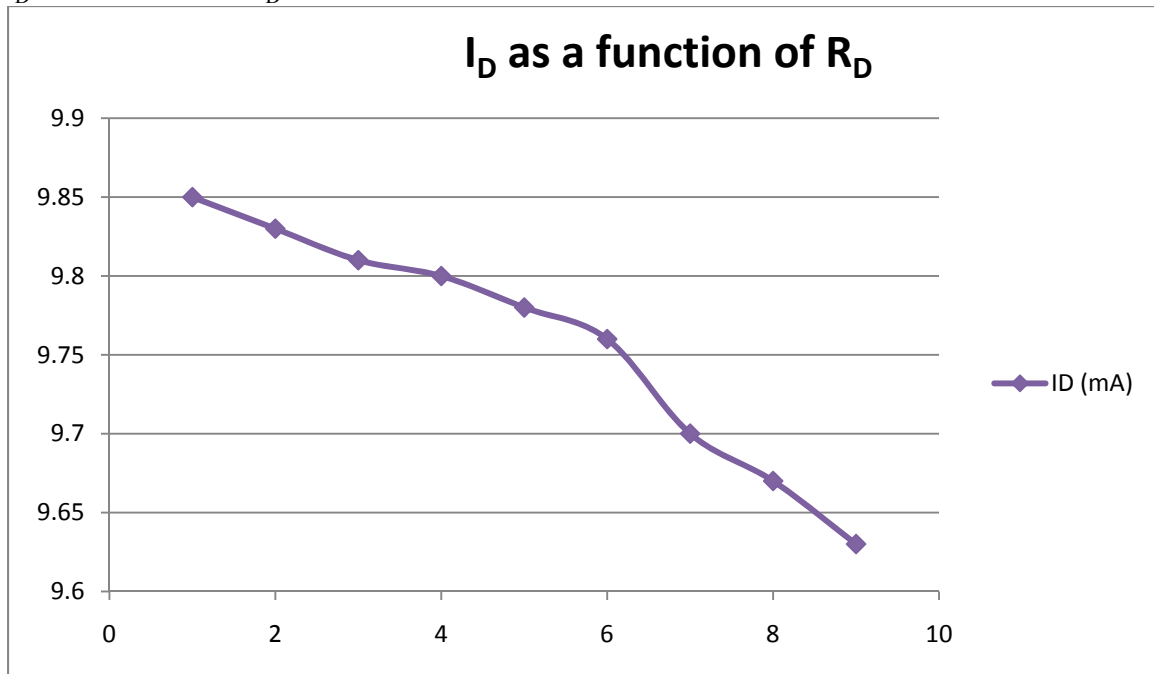
### E3. Measurements and results

$i$ - $R_D$ ,  $I_D$  and  $V_{DS}$

$R_D$	$I_D$ (mA)	$V_{DS}$ (V)
0 $\Omega$	9.85	9.9
100 $\Omega$	9.83	7.9
220 $\Omega$	9.81	6.8
330 $\Omega$	9.8	5.7
470 $\Omega$	9.78	4.4
560 $\Omega$	9.76	3.56
680 $\Omega$	9.7	2.54
820 $\Omega$	9.67	1.17
1 k $\Omega$	9.63	0.25

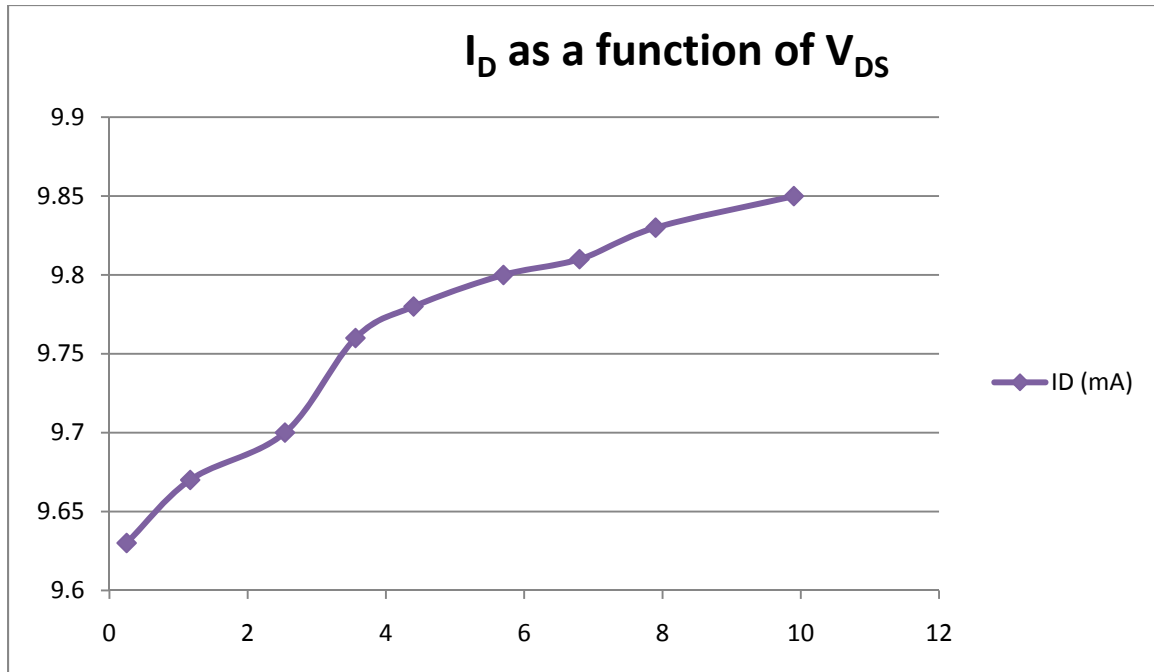
### E4. Discussions

$I_D$  as a function of  $R_D$



$I_D$  is not constant but is approximately stable when  $R$  is between 0 and 330 ohms.

$I_D$  as a function of  $V_{DS}$



The current is approximately constant when  $V$  varies between 9.9 and 5.7 V, this is when  $V_{DS}$  is in Saturation, since it is somehow independent of voltage at this region.

$$R_o = 1/\text{slope} = (9.9 - 0.25) / (9.85 - 9.63) = 43.863 \text{ ohms}$$

## VI-References

The lab manual in addition to the in Lab.

## VII-Mistakes and Problems faced in the Labs

Me and my fellow classmates were bothered a lot during the lab, as usual, the equipment is old and worn out therefore tend to malfunction.

For example, the instructor had to change our oscilloscope twice in order to get an acceptable reading.

In addition to the fact that the transformer wires were loose, and some didn't even have wires, we had to wait to attach a wire or 2 sometimes, which would fall back shortly after.

## VIII Signature

*I HAVE NEITHER GIVEN NOR RECEIVED AID ON THIS REPORT NOR HAVE I CONCEALED ANY VIOLATION OF THE AUB STUDENT CODE OF CONDUCT.*